ICDD Annual Spring Meetings – Review

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Members of the International Centre for Diffraction Data met during the week of 13 March 2017 for the Annual Spring Meetings. An unwelcomed guest, a Nor'easter named Stella, blew into town on Monday night and changed everyone's plans for Tuesday. The Plenary and Poster Session had to move to the Best Western Plus Concordville Hotel with limited staff participation. The remainder of the week's meetings took place as scheduled at ICDD Headquarters.

The Tuesday morning plenary session featured four speakers. **Justin Blanton**, Manager of Engineering and Design for International Centre for Diffraction Data, gave a talk on the *2017 Product Developments for ICDD Powder Diffraction File™ Software*. **Hideo Toraya**, Rigaku Corporation, Japan, spoke about *A New Method for Quantitative Phase Analysis of Multi-Component Polycrystalline Materials using Observed Integrated Intensities and Chemical Compositional Data of Individual Crystalline Phases.* **Luca Lutterotti**, University of Trento, Italy, gave a talk entitled *Toward a Fully Automatic Structural and Chemical Quantitative Analysis by X-ray*. **Vladislav Blatov**, Samara State University, Russia, chose his topic of discussion to be *Topological Information in Crystallography and Crystal Chemistry: A Route to Knowledge Databases*.

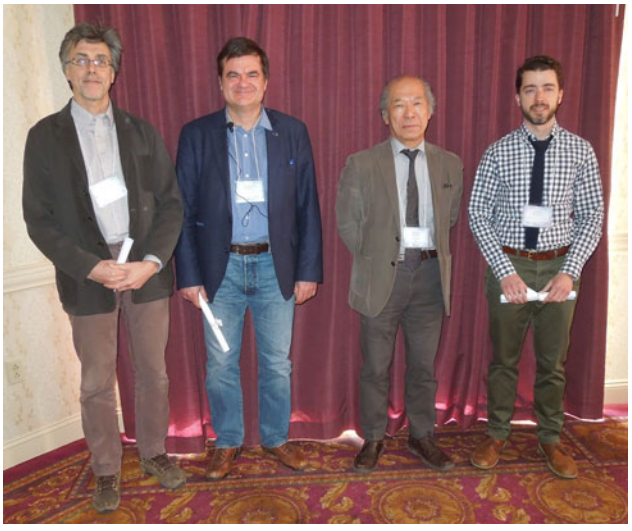


Photo 1. (Color online) Plenary Speakers (left to right): L. Lutterotti, V. Blatov, H. Toraya and J. Blanton.

Stephanie Jennings and Terry Maguire were on hand at the Best Western Plus Concordville Hotel for the poster session. They helped set the 27 posters on display for members and guests to view. Members were asked to vote on their favorite poster, and the posters receiving the most votes were on display at ICDD Headquarters for the remainder of the week. The three best posters were: *Decontamination of Powder Diffraction Data Measured with Copper Ka X-ray and Nickel Filter* presented by **Takashi Ida** of Advanced Ceramics Research Center, Nagoya Institute of Technology, Japan; *In Situ Study of the Phase Transformations in the Graphite Anodes by Rietveld Method* presented by **Aleksandr Missyul** of ALBA Synchrotron Light Source, Barcelona, Spain; *Simultaneous Texture and Strain Analysis of Additive Manufactured Parts via Tilt-A-Whirl Software,* presented by **Mark Rodriguez** of Sandia National Laboratories, Albuquerque, NM.

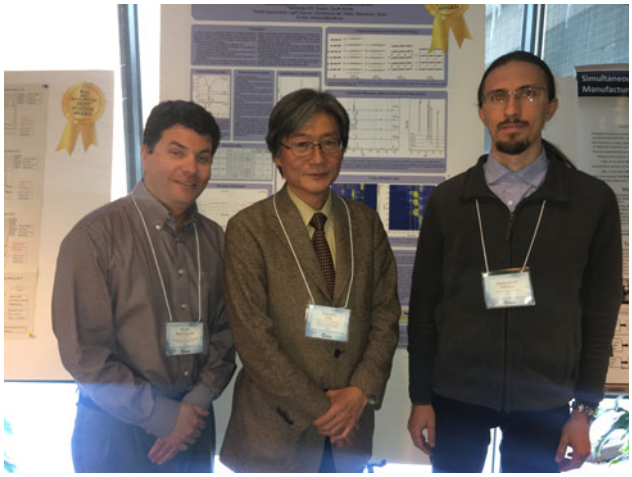


Photo 2. (Color online) Poster Session Winners (left to right): M. Rodriguez, T. Ida and A. Missyul.

The week concluded with the Annual Meeting of Members, on 16 March. The following awards were presented:
Certain members who have given long and meritorious service to ICDD, and are currently recognized as Fellows, may be granted the title of **Distinguished Fellow**. Matteo Leoni presented the Distinguished Fellow Award to **Winnie Wong-Ng** of the National Institute of Standards and Technology, Gaithersburg MD, honoring her service to the ICDD since 1981.

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Photo 3. (Color online) Winnie Wong-Ng receives the Distinguished Fellow Award from Chairman Matteo Leoni.

The designation of **Fellow** may be given by the ICDD Board of Directors to individuals who have given their time and talents beyond that normally associated with membership. Matteo Leoni announced the recipient of the Fellow Award as **Thomas Watkins**, of Oak Ridge National Laboratories, Oak Ridge TN. Tom was honored for his two decades of leadership at the Denver X-ray Conference and strong support of ICDD; the award will be presented at the Plenary Session of the 2017 Denver X-ray Conference.

Full details of the ICDD meetings, as well as abstracts for posters can be found at http://www.icdd.com/profile/march17.htm

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